

1.6-MHz Synchronous Switch-Mode Li-Ion and Li-Polymer Stand-Alone Battery Charger with Integrated MOSFETs and Power Path Selector

Check for Samples: bq24170, bq24172

FEATURES

- 1.6MHz Synchronous Switch-Mode Charger with 4A Integrated N-MOSFETs
- Up to 94% Efficiency
- 30V Input Rating with Adjustable Over-Voltage Protection
 - 4.5V to 17V Input Operating Voltage Range
- Battery Charge Voltage
 - bq24170: 1, 2, or 3-Cell with 4.2V/Cell
 - bq24172: Adjustable Charge Voltage
- High Integration
 - Automatic Power Path Selector Between Adapter and Battery
 - Dynamic Power Management
 - Integrated 20-V Switching MOSFETs
 - Integrated Bootstrap Diode
 - Internal Loop Compensation
 - Internal Digital Soft Start
- Safety
 - Thermal Regulation Loop Throttles Back Current to Limit T_i = 120°C
 - Thermal Shutdown
 - Battery Thermistor Sense Hot/Cold Charge Suspend & Battery Detect
 - Input Over-Voltage Protection with Programmable Threshold
 - Cycle-by-Cycle Current Limit
- Accuracy
 - ±0.5% Charge Voltage Regulation
 - ±4% Charge Current Regulation
 - ±4% Input Current Regulation
- Less than 15µA Battery Current with Adapter Removed
- Less than 1.5mA Input Current with Adapter Present and Charge Disabled
- Small QFN Package
 - 3.5mm × 5.5mm QFN-24 Pin

APPLICATIONS

- Tablet PC
- Netbook and Ultra-Mobile Computers
- Portable Data Capture Terminals
- Portable Printers
- Medical Diagnostics Equipment
- Battery Bay Chargers
- Battery Back-Up Systems

DESCRIPTION

The bq24170/172 is highly integrated stand-alone Li-ion and Li-polymer switch-mode battery charger with two integrated N-channel power MOSFETs. It offers a constant-frequency synchronous PWM controller with high accuracy regulation of input current, charge current, and voltage. It closely monitors the battery pack temperature to allow charge only in a preset temperature window. It also provides battery detection, pre-conditioning, charge termination, and charge status monitoring. The thermal regulation loop reduces charge current to maintain the junction temperature of 120°C during operation.

The bq24170/172 charges the battery in three phases: precondictioning, constant current, and constant voltage. The bq24170 charges one, two, or three cells (selected by CELL pin), and the bq24172 is adjustable for up to three series Li+ cells.

Charge is terminated when the current reaches 10% of the fast charge rate. A programmable charge timer offers a safety back up. The bq24170/172 automatically restarts the charge cycle if the battery voltage falls below an internal threshold, and enters a low-quiescent current sleep mode when the input voltage falls below the battery voltage.

The bq24170/172 features Dynamic Power Management (DPM) to reduce the charge current when the input power limit is reached to avoid over-loading the adapter. A highly-accurate current-sense amplifier enables precise measurement of input current from adapter to monitor overall system power.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

bq24170 bq24172 SLUSAD2B-NOVEMBER 2010-REVISED APRIL 2011



www.ti.com

These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

DESCRIPTION (CONTINUED)

The bq24170/172 provides power path selector gate driver ACDRV/CMSRC on input NMOS pair ACFET (Q1) and RBFET (Q2), and BATDRV on a battery PMOS device (Q3). When the qualified adapter is present, the system is directly connected to the adapter. Otherwise, the system is connected to the battery. In addition, the power path prevents battery from boosting back to the input.

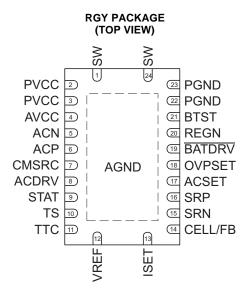
The bq24170/172 charges a battery from a DC source as high as 17V, including a car battery. The input over-voltage limit is adjustable through the OVPSET pin. The AVCC, ACP, and ACN pins have a 30V rating. When a high voltage DC source is inserted, Q1/Q2 remain off to avoid high voltage damage to the system.

For 1 cell applications, if the battery is not removable, the system can be directly connected to the battery to simplify the power path design and lower the cost. With this configuration, the battery can automatically supplement the system load if the adapter is overloaded.

The bq24170/172 is available in a 24-pin, 3.5mm x 5.5mm thin QFN package.

PIN FUNCTIONS

PIN TYPE DESCRIPTION NO. NAME 1,24 SW Р Switching node, charge current output inductor connection. Connect the 0.047-µF bootstrap capacitor from SW to BTST. Ρ 2,3 **PVCC** Charger input voltage. Connect at least 10-µF ceramic capacitor from PVCC to PGND and place it as close as possible to IC. 4 AVCC Ρ IC power positive supply. Place a 1-µF ceramic capacitor from AVCC to AGND and place it as close as possible to IC. Place a 10-Ω resistor from input side to AVCC pin to filter the noise. For 5V input, a 5-Ω resistor is recommended. ACN L Adapter current sense resistor negative input. A 0.1-µF ceramic capacitor is placed from ACN to ACP to 5 provide differential-mode filtering. An optional 0.1-uF ceramic capacitor is placed from ACN pin to AGND for common-mode filtering. Adapter current sense resistor positive input. A 0.1-µF ceramic capacitor is placed from ACN to ACP to ACP P/I 6 provide differential-mode filtering. A 0.1-µF ceramic capacitor is placed from ACP pin to AGND for common-mode filtering. 7 CMSRC 0 Connect to common source of N-channel ACFET and reverse blocking MOSFET (RBFET). Place 4-kΩ resistor from CMSRC pin to the common source of ACFET and RBFET to control the turn-on speed. The resistance between ACDRV and CMSRC should be 500-kΩ or bigger. 8 ACDRV 0 AC adapter to system switch driver output. Connect to 4-kΩ resistor then to the gate of the ACFET N-channel power MOSFET and the reverse conduction blocking N-channel power MOSFET. Connect both FETs as common-source. The internal gate drive is asymmetrical, allowing a quick turn-off and slower turn-on in addition to the internal break-before-make logic with respect to the BATDRV. Open-drain charge status pin with 10-k Ω pull up to power rail. The STAT pin can be used to drive LED or 9 STAT 0 communicate with the host processor. It indicates various charger operations: LOW when charge in progress. HIGH when charge is complete or in SLEEP mode. Blinking at 0.5Hz when fault occurs, including charge suspend, input over-voltage, timer fault and battery absent. Temperature qualification voltage input. Connect a negative temperature coefficient thermistor. Program TS I 10 the hot and cold temperature window with a resistor divider from VREF to TS to AGND. The temperature qualification window can be set to 5-40°C or wider. The 103AT thermistor is recommended.





PIN FUNCTIONS (continued)

	PIN	TYPE	DESCRIPTION			
NO.	NAME	TIFE	DESCRIPTION			
11	TTC	Ι	Safety Timer and termination control. Connect a capacitor from this node to AGND to set the fast charge safety timer(5.6min/nF). Pre-charge timer is internally fixed to 30 minutes. Pull the TTC to LOW to disable the charge termination and safety timer. Pull the TTC to HIGH to disable the safety timer but allow the charge termination.			
12	VREF	Ρ	3.3V reference voltage output. Place a 1- μ F ceramic capacitor from VREF to AGND pin close to the IC. This voltage could be used for programming ISET and ACSET and TS pins. It may also serve as the pull-up rail of STAT pin and CELL pin.			
13	ISET	I	Fast charge current set point. Use a voltage divider from VREF to ISET to AGND to set the fast charge current:			
			$I_{CHG} = \frac{V_{ISET}}{20 \times R_{SR}}$			
			The pre-charge and termination current is internally as one tenth of the charge current. The charger is disabled when ISET pin voltage is below 40mV and enabled when ISET pin voltage is above 120mV.			
14	CELL (bq24170)	I	Cell selection pin. Set CELL pin LOW for 1-cell, Float for 2-cell (0.8V-1.8V), and HIGH for 3-cell with a fixed 4.2V per cell.			
	FB (bq24172)		Charge voltage analog feedback adjustment. Connect the output of a resistor divider powered from the battery terminals to VFB to AGND. Output voltage is regulated to 2.1V on FB pin during constant-voltage mode.			
15	SRN	I	Charge current sense resistor negative input. A 0.1-µF ceramic capacitor is placed from SRN to SRP to provide differential-mode filtering. A 0.1-µF ceramic capacitor is placed from SRN pin to AGND for common-mode filtering.			
16	SRP	I/P	Charge current sense resistor, positive input. A 0.1-µF ceramic capacitor is placed from SRN to SRP to provide differential-mode filtering. A 0.1-µF ceramic capacitor is placed from SRP pin to AGND for common-mode filtering.			
17	ACSET	I	Input current set point. Use a voltage divider from VREF to ACSET to AGND to set this value:			
			$I_{DPM} = \frac{V_{ACSET}}{20 \times R_{AC}}$			
18	OVPSET	I	Valid input voltage set point. Use a voltage divider from input to OVPSET to AGND to set this voltage. The voltage above internal 1.6V reference indicates input over-voltage, and the voltage below internal 0.5V reference indicates input under-voltage. In either condition, charge terminates, and input NMOS pair ACFET/RBFET turn off. LED driven by STAT pin keeps blinking, reporting fault condition.			
19	BATDRV	0	Battery discharge MOSFET gate driver output. Connect to 1kohm resistor to the gate of the BATFET P-channel power MOSFET. Connect the source of the BATFET to the system load voltage node. Connect the drain of the BATFET to the battery pack positive node. The internal gate drive is asymmetrical to allow a quick turn-off and slower turn-on, in addition to the internal break-before-make logic with respect to ACDRV.			
20	REGN	Р	PWM low side driver positive 6V supply output. Connect a 1-µF ceramic capacitor from REGN to PGND pin, close to the IC. Generate high-side driver bootstrap voltage by integrated diode from REGN to BTST.			
21	BTST	Р	PWM high side driver positive supply. Connect the 0.047-µF bootstrap capacitor from SW to BTST.			
22,23	PGND	Р	Power ground. Ground connection for high-current power converter node. On PCB layout, connect directly to ground connection of input and output capacitors of the charger. Only connect to AGND through the Thermal Pad underneath the IC.			
Thermal Pad	AGND	Ρ	Exposed pad beneath the IC. Always solder Thermal Pad to the board, and have vias on the Thermal Pad plane star-connecting to AGND and ground plane for high-current power converter. It dissipates the heat from the IC.			

TEXAS INSTRUMENTS www.ti.com

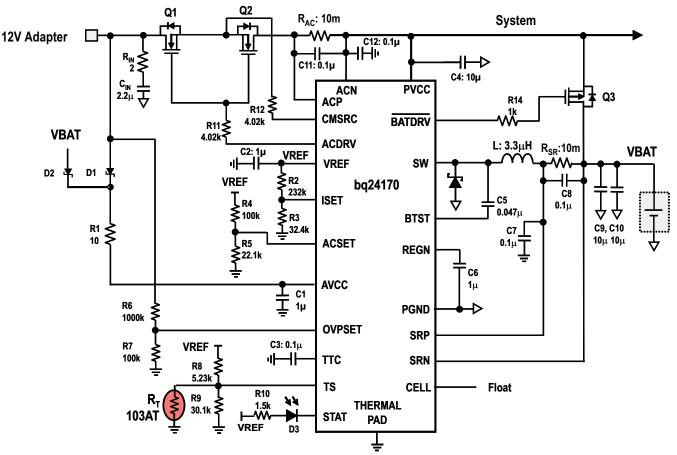


Figure 1. Typical Application Schematic (12V input, 2 cell battery 8.4V, 2A charge current, 0.2A pre-charge/termination current, 3A DPM current, 18V input OVP, 0 – 45°C TS)



bq24170 bq24172 SLUSAD2B-NOVEMBER 2010-REVISED APRIL 2011

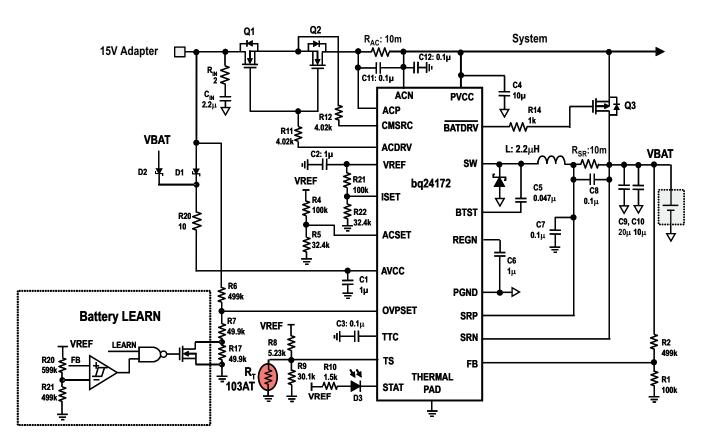


Figure 2. Typical Application Schematic with Battery Learn Function (15V input, 3 cell battery 12.6V, 4A charge current, 0.4A pre-charge/termination current, 4A DPM current, 0 – 45°C TS)

bq24170 bq24172 SLUSAD2B – NOVEMBER 2010–REVISED APRIL 2011



www.ti.com

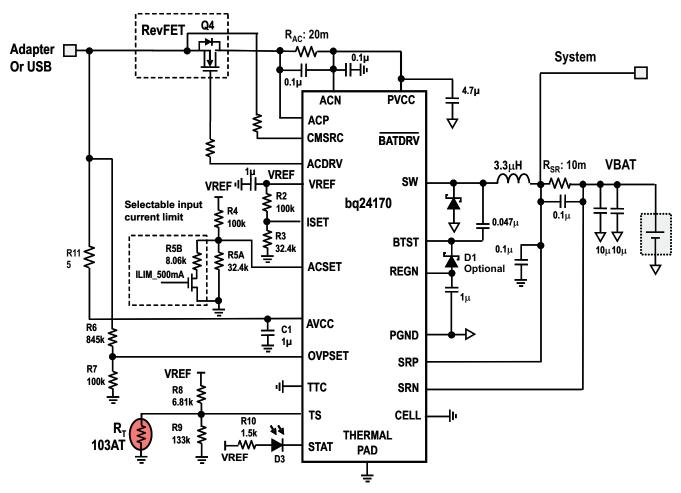


Figure 3. Typical Application Schematic wth Single Cell Unremovable Battery (USB or adapter with input OVP 15V, up to 4A charge current, 0.4A pre-charge current, 2A adapter current or 500mA USB current, $5 - 40^{\circ}$ C TS, system connected before sense resistor)



bq24170 bq24172 SLUSAD2B – NOVEMBER 2010 – REVISED APRIL 2011

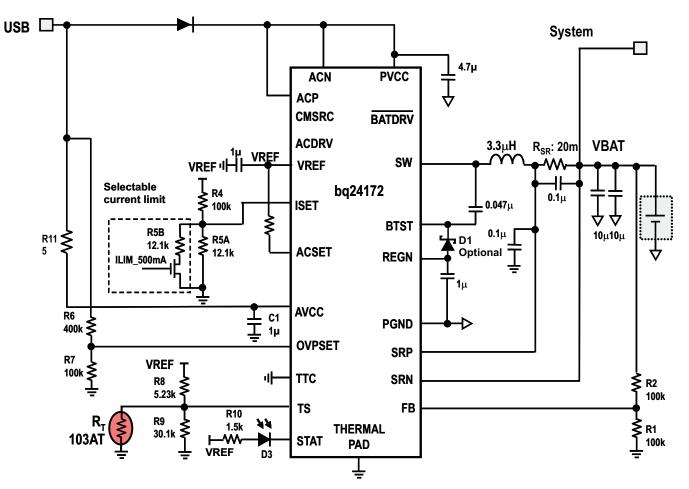


Figure 4. Typical Application Schematic with Single Cell Unremovable Battery (USB with input OVP 8V, selectable charge current limit of 900mA or 500mA, 0 – 45°C TS, system connected after sense resistor)

PART NUMBER	PART MARKING	PACKAGE	ORDERING NUMBER	QUANTITY	
h=04470				3000	
bq24170	bq24170 bq24170 24-Pin 3.5mm×5.5m		bq24170RGYT	250	
h = 0.4470	h=04470		bq24172RGYR	3000	
bq24172	bq24172	24-Pin 3.5mm×5.5mm QFN	bq24172RGYT	250	

ORDERING INFORMATION⁽¹⁾

For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.

SLUSAD2B-NOVEMBER 2010-REVISED APRIL 2011

ISTRUMENTS

EXAS

www.ti.com

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted) (1)(2)

		VALUE	UNIT
	PVCC	-0.3 to 20	
	AVCC, ACP, ACN, ACDRV, CMSRC, STAT	-0.3 to 30	
Voltage range (with respect to AGND)	BTST	-0.3 to 26	
	BATDRV, SRP, SRN	-0.3 to 20	
	SW	-2 to 20	V
	FB (bq24172)	–0.3 to 16	
	OVPSET, REGN, TS, TTC, CELL (bq24170)	–0.3 to 7	
	VREF, ISET, ACSET	-0.3 to 3.6	
	PGND	-0.3 to 0.3	
Maximum difference voltage	SRP–SRN, ACP-ACN	–0.5 to 0.5	V
Junction temperature range, T_J		-40 to 155	°C
Storage temperature range, T _{stg}		-55 to 155	°C

(1) Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltages are with respect to GND if not specified. Currents are positive into, negative out of the specified terminal. Consult Packaging Section of the data book for thermal limitations and considerations of packages.

THERMAL INFORMATION

	THERMAL METRIC ⁽¹⁾	bq24170/2 RGY 24 PINS	UNITS
θ_{JA}	Junction-to-ambient thermal resistance ⁽²⁾	35.7	
Ψ_{JT}	Junction-to-top characterization parameter ⁽³⁾	0.4	°C/W
Ψ _{JB}	Junction-to-board characterization parameter ⁽⁴⁾	31.2	

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

(2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.

(3) The junction-to-top characterization parameter, ψ_{JT} , estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA} , using a procedure described in JESD51-2a (sections 6 and 7).

(4) The junction-to-board characterization parameter, ψ_{JB} , estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA} , using a procedure described in JESD51-2a (sections 6 and 7).

RECOMMENDED OPERATING CONDITIONS

		MIN	MAX	UNIT
Input voltage	V _{IN}	4.5	17	V
Output voltage	V _{OUT}		13.5	V
Output current (R _{SR} 10mΩ)	I _{OUT}	0.6	4	А
Maximum difforance valtage	ACP - ACN	-200	200	mV
Maximum difference voltage	SRP-SRN	-200	200	mV
Operation free-air temperature	range, T _A	-40	85	°C



ELECTRICAL CHARACTERISTICS

 $4.5V \le V(PVCC, AVCC) \le 17V, -40^{\circ}C < T_{J} + 125^{\circ}C$, typical values are at $T_{A} = 25^{\circ}C$, with respect to AGND (unless otherwise the transmission of transmission of the transmission of tr noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
OPERATING C	ONDITIONS					
V _{AVCC_OP}	AVCC input voltage operating range during charging		4.5		17	V
QUIESCENT C	URRENTS					
		V_{AVCC} > V_{UVLO} , V_{SRN} > V_{AVCC} (SLEEP), T_J = 0°C to 85°C			15	
I _{BAT}	Battery discharge current (sum of currents into AVCC, PVCC, ACP, ACN)	BTST, SW, SRP, SRN, $V_{AVCC} > V_{UVLO}$, $V_{AVCC} > V_{SRN}$, ISET < 40mV, V_{BAT} =12.6V, Charge disabled			25	μA
		BTST, SW, SRP, SRN, $V_{AVCC} > V_{UVLO}$, $V_{AVCC} > V_{SRN}$, ISET > 120mV, V_{BAT} =12.6V, Charge done			25	
		V _{AVCC} > V _{UVLO} , V _{AVCC} > V _{SRN} , ISET < 40mV, V _{BAT} =12.6V, Charge disabled		1.2	1.5	
I _{AC}	Adapter supply current (sum of current into AVCC,ACP, ACN)	V _{AVCC} > V _{UVLO} , V _{AVCC} > V _{SRN} , ISET > 120mV, Charge enabled, no switching		2.5	5	mA
		V _{AVCC} > V _{UVLO} , V _{AVCC} > V _{SRN} , ISET > 120mV, Charge enabled, switching		15 ⁽¹⁾		
CHARGE VOLT	TAGE REGULATION					
		CELL to AGND, 1 cell, measured on SRN		4.2		V
V _{BAT_REG}	SRN regulation voltage (bq24170)	CELL floating, 2 cells, measured on SRN		8.4		V
		CELL to VREF, 3 cells, measured on SRN		12.6		V
V _{FB REG}	Feddback regulation voltage (bg24172)	Measured on FB		2.1		V
10_110	5 5 (1)	$T_{ij} = 0^{\circ}C \text{ to } 85^{\circ}C$	-0.5%		0.5%	
	Charge voltage regulation accuracy	$T_{\rm I} = -40^{\circ}$ C to 125°C	-0.7%		0.7%	
I _{FB}	Leakage current into FB pin (bg24172)	V _{FB} = 2.1 V			100	nA
	GULATION – FAST CHARGE	10				
VISET	ISET Voltage Range	$R_{SENSE} = 10m\Omega$	0.12		0.8	V
K _{ISET}	Charge Current Set Factor (Amps of Charge Current per Volt on ISET pin)	$R_{SENSE} = 10m\Omega$		5		A/V
	Charge Current Regulation Accuracy	V _{SRP-SRN} = 40 mV	-4%		4%	
		$V_{\text{SRP-SRN}} = 20 \text{ mV}$	-7%		7%	
	(with Schottky diode on SW)	$V_{\text{SRP-SRN}} = 5 \text{ mV}$	-25%		25%	
V _{ISET_CD}	Charge Disable Threshold	ISET falling	40	50		mV
V _{ISET_CE}	Charge Enable Threshold	ISET rising		100	120	mV
I _{ISET}	Leakage Current into ISET	VISET = 2V			100	nA
K _{DPM}	Input DPM Current Set Factor (Amps of Input Current per Volt on ACSET)	$R_{SENSE} = 10m\Omega$		5		A/V
	,	V _{ACP-ACN} = 80 mV	-4%		4%	
		$V_{ACP-ACN} = 40 \text{ mV}$	-9%		9%	
	Input DPM Current Regulation Accuracy	$V_{ACP-ACN} = 20 \text{ mV}$	-15%		15%	
	(with Schottky diode on SW)	$V_{ACP-ACN} = 5 \text{ mV}$	-20%		20%	
		$V_{ACP-ACN} = 0.000$ $V_{ACP-ACN} = 2.5 \text{ mV}$	-40%		40%	
IACSET	Leakage Current into ACSET pin	V _{ACSET} = 2V			100	nA
	SULATION – PRE-CHARGE				100	
K _{IPRECHG}	Precharge current set factor	Percentage of fast charge current		10% ⁽²⁾		
· YPKEURG		$V_{\text{SRP-SRN}} = 4 \text{ mV}$	-25%	1070	25%	
	Precharge current regulation accuracy	* 5KP-5KN = + 111V	2070		2070	

TEXAS INSTRUMENTS

www.ti.com

ELECTRICAL CHARACTERISTICS (continued)

 $4.5V \le V(PVCC, AVCC) \le 17V, -40^{\circ}C < T_{J} + 125^{\circ}C$, typical values are at $T_{A} = 25^{\circ}C$, with respect to AGND (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
CHARGE TERMIN	ATION		1			
K _{TERM}	Termination current set factor	Percentage of fast charge current		10% ⁽³⁾		
	Termination current regulation accuracy	V _{SRP-SRN} = 4 mV	-25%		25%	
		V _{SRP-SRN} = 2 mV	-40%		40%	
term_deg	Deglitch time for termination (both edges)			100		ms
t _{qual}	Termination qualification time	$V_{SRN} > V_{RECH}$ and $I_{CHG} < I_{TERM}$		250		ms
QUAL	Termination qualification current	Discharge current once termination is detected		2		mA
INPUT UNDER-VO	LTAGE LOCK-OUT COMPARATOR (UVLO)					
V _{UVLO}	AC under-voltage rising threshold	Measure on AVCC	3.4	3.6	3.8	V
V _{UVLO_HYS}	AC under-voltage hysteresis, falling	Measure on AVCC		300		mV
SLEEP COMPARA	TOR (REVERSE DISCHARGING PROTECTIO	DN)				
V _{SLEEP}	SLEEP mode threshold	V _{AVCC} – V _{SRN} falling	50	90	150	mV
V _{SLEEP_HYS}	SLEEP mode hysteresis	V _{AVCC} – V _{SRN} rising		200		mV
SLEEP_FALL_CD	SLEEP deglitch to disable charge	V _{AVCC} – V _{SRN} falling		1		ms
SLEEP_FALL_FETOFF	SLEEP deglitch to turn off input FETs	V _{AVCC} – V _{SRN} falling		5		ms
t _{SLEEP_FALL}	Deglitch to enter SLEEP mode, disable VREF and enter low quiescent mode	V _{AVCC} – V _{SRN} falling		100		ms
SLEEP_PWRUP	Deglitch to exit SLEEP mode, and enable VREF	$V_{AVCC} - V_{SRN}$ rising		30		ms
ACN-SRN COMPA	RATOR					
V _{ACN-SRN}	Threshold to turn on BATFET	V _{ACN-SRN} falling	150	220	300	mV
VACN-SRN_HYS	Hysteresis to turn off BATFET	V _{ACN-SRN} rising		100		mV
BATFETOFF_DEG	Deglitch to turn on BATFET	V _{ACN-SRN} falling		2		ms
BATFETON_DEG	Deglitch to turn off BATFET	V _{ACN-SRN} rising		50		μs
BAT LOWV COMP	ARATOR					
	Precharge to fast charge transition	bq24170, CELL to AGND, 1 cell, measure on SRN	2.87	2.9	2.93	
V _{LOWV}		bq24170, CELL floating, 2 cells, measure on SRN	5.74	5.8	5.86	V
		bq24170, CELL to VREF, 3 cells, measure on SRN	8.61	8.7	8.79	
		bq24172, measure on FB	1.43	1.45	1.47	
		bq24170, CELL to AGND, 1 cell, measure on SRN		200		
V _{LOWV_HYS}	Fast charge to precharge hysteresis	bq24170, CELL floating, 2 cells, measure on SRN		400		mV
		bq24170, CELL to VREF, 3 cells, measure on SRN		600		
		bq24172, measure on FB		100		
pre2fas	V _{LOWV} rising deglitch	Delay to start fast charge current		25		ms
fast2pre	V _{LOWV} falling deglitch	Delay to start precharge current		25		ms
RECHARGE COMP	PARATOR					
		bq24170, CELL to AGND, 1 cell, measure on SRN	70	100	130	
V _{RECHG}	Recharge Threshold, below regulation voltage limit, V_{BAT_REG} - V_{SRN} (bq24170), or	bq24170, CELL floating, 2 cells, measure on SRN	140	200	260	mV
	V _{FB_REG} -V _{FB} (bq24172)	bq24170, CELL to VREF, 3 cells, measure on SRN	210	300	390	
		bq24172, measure on FB	35	50	65	
RECH_RISE_DEG	V _{RECHG} rising deglitch	VFB decreasing below V _{RECHG}		10		ms
t _{RECH_FALL_DEG}	V _{RECHG} falling deglitch	VFB increasing above V _{RECHG}		10		ms

(3) The minimum current is 120 mA on $10m\Omega$ sense resistor.



ELECTRICAL CHARACTERISTICS (continued)

 $4.5V \le V(PVCC, AVCC) \le 17V, -40^{\circ}C < T_{J} + 125^{\circ}C$, typical values are at $T_{A} = 25^{\circ}C$, with respect to AGND (unless otherwise noted)

loted)	PARAMETER	TEST CONDITIONS	MIN	ТҮР	MAX	UNITS
BAT OVER-VOLT	AGE COMPARATOR		MIIN		шал	onnine
V _{OV_RISE}	Over-voltage rising threshold	As percentage of V _{BAT_REG} (bq24170) or V _{FB_REG} (bq24172)		104%		
V _{OV_FALL}	Over-voltage falling threshold	As percentage of V _{SRN} (bq24170) or V _{FB_REG} (bq24172)		102%		
INPUT OVER-VOI	LTAGE COMPARATOR (ACOV)					
V _{ACOV}	AC Over-Voltage Rising Threshold to turn off ACFET	OVPSET rising	1.57	1.6	1.63	V
V _{ACOV_HYS}	AC over-voltage falling hysteresis	OVPSET falling		50		mV
ACOV_RISE_DEG	AC Over-Voltage Rising Deglitch to turn off ACFET and Disable Charge	OVPSET rising		1		μs
t _{ACOV_FALL_DEG}	AC Over-Voltage Falling Deglitch to Turn on ACFET	OVPSET falling		30		ms
INPUT UNDER-VO	OLTAGE COMPARATOR (ACUV)	·				
V _{ACUV}	AC Under-Voltage Falling Threshold to turn off ACFET	OVPSET falling	0.487	0.497	0.507	V
V _{ACUV_HYS}	AC Under-Voltage Rising Hysteresis	OVPSET rising		100		mV
t _{ACOV_FALL_DEG}	AC Under-Voltage Falling Deglitch to turn off ACFET and Disable Charge	OVPSET falling		1		μs
t _{ACOV_RISE_DEG}	AC Under-Voltage Rising Deglitch to turn on ACFET	OVPSET rising		30		ms
THERMAL REGU	LATION					
T _{J_REG}	Junction Temperature Regulation Accuracy	ISET > 120mV, Charging		120		°C
THERMAL SHUT	DOWN COMPARATOR					
T _{SHUT}	Thermal shutdown rising temperature	Temperature rising		150		°C
T _{SHUT_HYS}	Thermal shutdown hysteresis	Temperature falling		20		°C
SHUT_RISE_DEG	Thermal shutdown rising deglitch	Temperature rising		100		μs
t _{SHUT_FALL_DEG}	Thermal shutdown falling deglitch	Temperature falling		10		ms
THERMISTOR CO	OMPARATOR					
V _{LTF}	Cold Temperature Threshold, TS pin Voltage Rising Threshold	Charger suspends charge. As percentage to $V_{\mbox{\scriptsize VREF}}$	72.5%	73.5%	74.5%	
V _{LTF_HYS}	Cold Temperature Hysteresis, TS pin Voltage Falling	As percentage to V _{VREF}	0.2%	0.4%	0.6%	
V _{HTF}	Hot Temperature TS pin voltage rising Threshold	As percentage to V _{VREF}	46.6%	47.2%	48.8%	
V _{TCO}	Cut-off Temperature TS pin voltage falling Threshold	As percentage to V_{VREF}	44.2%	44.7%	45.2%	
TS_CHG_SUS	Deglitch time for Temperature Out of Range Detection	$V_{TS} > V_{LTF}$, or $V_{TS} < V_{TCO}$, or $V_{TS} < V_{HTF}$		20		ms
ts_chg_resume	Deglitch time for Temperature in Valid Range Detection	V_{TS} < V_{LTF} – V_{LTF_HYS} or V_{TS} >V_{TCO}, or V_{TS} > V_{HTF}		400		ms
CHARGE OVER-C	CURRENT COMPARATOR (CYCLE-BY-CYCLE)					
V _{OCP_CHRG}	Charge Over-Current Rising Threshold, V _{SRP} >2.2V	Current as percentage of fast charge current		160%		
V _{OCP_MIN}	Charge Over-Current Limit Min, V _{SRP} <2.2V	Measure V _{SRP-SRN}		45		mV
V _{OCP_MAX}	Charge Over-Current Limit Max, V _{SRP} >2.2V	Measure V _{SRP-SRN}		75		mV
HSFET OVER-CU	RRENT COMPARATOR (CYCLE-BY-CYCLE)					
IOCP_HSFET	Current limit on HSFET	Measure on HSFET	8	11.5		Α
CHARGE UNDER	-CURRENT COMPARATOR (CYCLE-BY-CYCLI	Ξ)				
V _{UCP}	Charge under-current falling threshold	Measure on V _(SRP-SRN)	1	5	9	mV



ELECTRICAL CHARACTERISTICS (continued)

 $4.5V \le V(PVCC, AVCC) \le 17V, -40^{\circ}C < T_{J} + 125^{\circ}C$, typical values are at $T_{A} = 25^{\circ}C$, with respect to AGND (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
BAT SHORT CO	MPARATOR					
V _{BATSHT}	Battery short falling threshold	Measure on SRN		2		V
V _{BATSHT_HYS}	Battery short rising hysteresis	Measure on SRN		200		mV
t _{BATSHT_DEG}	Deglitch on both edges			1		μs
V _{BATSHT}	Charge Current during BATSHORT	Percentage of fast charge current		10% ⁽⁴⁾		
VREF REGULAT	OR					
V _{VREF_REG}	VREF regulator voltage	V _{AVCC} > V _{UVLO} , No load	3.267	3.3	3.333	V
I _{VREF_LIM}	VREF current limit	$V_{VREF} = 0 V, V_{AVCC} > V_{UVLO}$	35		90	mA
REGN REGULAT	TOR					
V _{REGN_REG}	REGN regulator voltage	V _{AVCC} > 10 V, ISET > 120 mV	5.7	6.0	6.3	V
I _{REGN_LIM}	REGN current limit	V _{REGN} = 0 V, V _{AVCC} > 10 v, ISET > 120 mV	40		120	mA
TTC INPUT		- I				
t _{prechrg}	Precharge Safety Timer	Precharge time before fault occurs	1620	1800	1980	Sec
t _{fastchrg}	Fast Charge Timer Range	T _{chg} =C _{TTC} *K _{TTC}	1		10	hr
	Fast Charge Timer Accuracy		-10%		10%	
K _{TTC}	Timer Multiplier			5.6		min/nF
V _{TTC_LOW}	TTC Low Threshold	TTC falling			0.4	V
	TTC Source/Sink Current		45	50	55	μA
V _{TTC_OSC_HI}	TTC oscillator high threshold			1.5		V
V _{TTC OSC LO}	TTC oscillator low threshold			1		V
	CH (BATFET) DRIVER	-			1	
R _{DS_BAT_OFF}	BATFET Turn-off Resistance	V _{AVCC} > 5V			100	Ω
R _{DS_BAT_ON}	BATFET Turn-on Resistance	V _{AVCC} > 5V			20	kΩ
V _{BATDRV_REG}	BATFET Drive Voltage	V_{BATDRV_REG} =V_{ACN} - V_{BATDRV} when V_{AVCC} > 5V and BATFET is on	4.2		7	V
t _{BATFET_DEG}	BATFET Power-up Delay to turn off BATFET after adapter is detected			30		ms
AC SWITCH (AC	FET) DRIVER	- I				
I _{ACFET}	ACDRV Charge Pump Current Limit	V _{ACDRV} - V _{CMSRC} = 5V		60		μA
V _{ACDRV_REG}	Gate Drive Voltage on ACFET	V _{ACDRV} - V _{CMSRC} when V _{AVCC} > V _{UVLO}	4.2	6		V
R _{ACDRV_LOAD}	Maximum load between ACDRV and CMSRC		500			kΩ
AC/BAT SWITCH	H DRIVER TIMING					
t _{DRV_DEAD}	Driver Dead Time	Dead Time when switching between ACFET and BATFET		10		μs
BATTERY DETE	CTION					
t _{WAKE}	Wake timer	Max time charge is enabled		500		ms
I _{WAKE}	Wake current	$R_{SENSE} = 10 \text{ m}\Omega$	50	125	200	mA
t _{DISCHARGE}	Discharge timer	Max time discharge current is applied		1		sec
IDISCHARGE	Discharge current			8		mA
I _{FAULT}	Fault current after a timeout fault			2		mA
	Wake threshold with respect to V_{REG} To	Measure on SRN (bq24170)		100		mV/cell
V _{WAKE}	detect battery absent during WAKE	Measure on FB (bq24172)		50		mV
	Discharge Threshold to detect battery	Measure on SRN (bq24170)		2.9		V/cell
V _{DISCH}	absent during discharge	Measure on VFB (bg24172)		1.45		V

(4) The minimum current is 120 mA on $10m\Omega$ sense resistor.



ELECTRICAL CHARACTERISTICS (continued)

 $4.5V \le V(PVCC, AVCC) \le 17V, -40^{\circ}C < T_J + 125^{\circ}C$, typical values are at $T_A = 25^{\circ}C$, with respect to AGND (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
INTERNAL PWM						
fsw	PWM Switching Frequency		1360	1600	1840	kHz
t _{SW_DEAD}	Driver Dead Time ⁽⁵⁾	Dead time when switching between LSFET and HSFET no load		30		ns
R _{DS_HI}	High Side MOSFET On Resistance	$V_{BTST} - V_{SW} = 4.5 V$		25	45	mΩ
R _{DS_LO}	Low Side MOSFET On Resistance			60	110	mΩ
	Bootstrap Refresh Comparator Threshold	$V_{BTST}-V_{SW}$ when low side refresh pulse is requested, $V_{AVCC}{=}4.5V$	3			V
V _{BTST_REFRESH}	Voltage	$V_{BTST}-V_{SW}$ when low side refresh pulse is requested, $V_{AVCC}{\!\!\!>}6V$	4			v
INTERNAL SOFT	START (8 steps to regulation current ICHG)					
SS_STEP	Soft start steps			8		step
T _{SS_STEP}	Soft start step time			1.6	3	ms
CHARGER SECT	TON POWER-UP SEQUENCING					
t _{CE_DELAY}	Delay from ISET above 120mV to start charging battery			1.5		S
INTEGRATED BT	IST DIODE					
V _F	Forward Bias Voltage	I _F =120mA at 25°C		0.85		V
V _R	Reverse breakdown voltage	I _R =2uA at 25°C			20	V
LOGIC IO PIN CH	HARACTERISTICS (STAT1, STAT2, TERM_EN)					
V _{OUT_LO}	STAT Output Low Saturation Voltage	Sink Current = 5 mA			0.5	V
V _{CELL_LO}	CELL pin input low threshold, 1 cell (bq24170)	CELL pin voltage falling edge			0.5	V
V _{CELL_MID}	CELL pin input mid threshold, 2 cells (bq24170)	CELL pin voltage rising for MIN, falling for MAX	0.8		1.8	V
V _{CELL_HI}	CELL pin input high threshold, 3 cells (bq24170)	CELL pin voltage rising edge	2.5			V

(5) Specified by design

TEXAS INSTRUMENTS

www.ti.com

TYPICAL CHARACTERISTICS

Table 1. Table of Graphs⁽¹⁾

FIGURE	DESCRIPTION
Figure 5	AVCC, VREF, ACDRV and STAT Power Up (ISET=0)
Figure 6	Charge Enable by ISET
Figure 7	Current Soft Start
Figure 8	Charge Disable by ISET
Figure 9	Continuous Conduction Mode Switching
Figure 10	Discontinuous Conduction Mode Switching
Figure 11	BATFET to ACFET Transition during Power Up
Figure 12	System Load Transient (Input Current DPM)
Figure 13	Battery Insertion and Removal
Figure 14	Battery to Ground Short Protection
Figure 15	Battery to Ground Short Transition
Figure 16	Efficiency vs Output Current (VIN=15V)
Figure 17	Efficiency vs Output Current (VOUT=3.8V)

(1) All waveforms and data are measured on HPA610 and HPA706 EVMs.

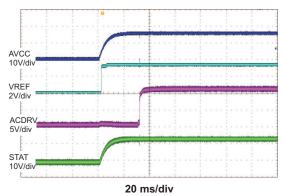


Figure 5. Power Up (ISET = 0)

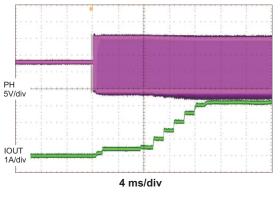


Figure 7. Current Soft Start

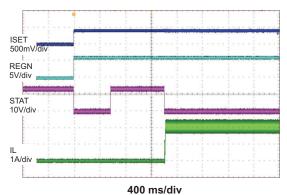


Figure 6. Charge Enable by ISET

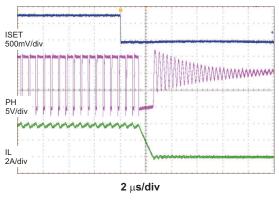


Figure 8. Charge Disable by ISET



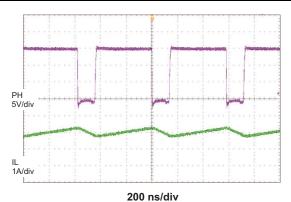


Figure 9. Continuous Conduction Mode Switching

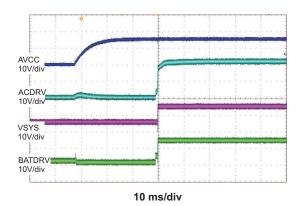


Figure 11. BATFET to ACFET Transition During Powerup

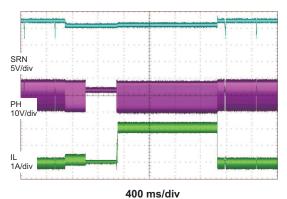


Figure 13. Battery Insertion and Removal



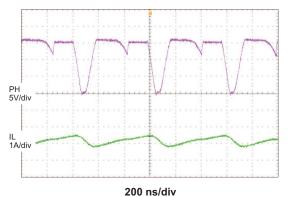


Figure 10. Discontinuous Conduction Mode Switching

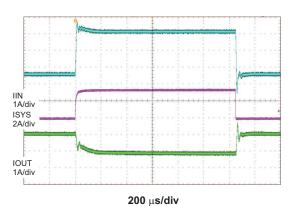


Figure 12. System Load Transient (Input current DPM)

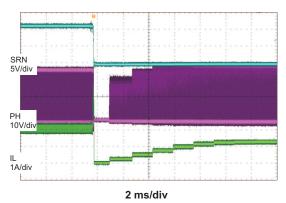
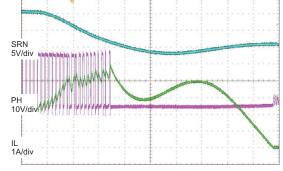


Figure 14. Battery to Ground Short Protection





4 $\mu\text{s/div}$ Figure 15. Battery to Ground Short Transition

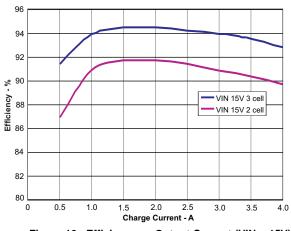


Figure 16. Efficiency vs Output Current (VIN = 15V)

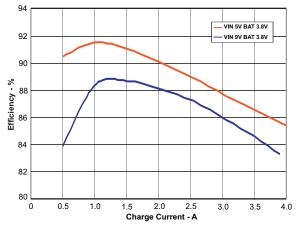
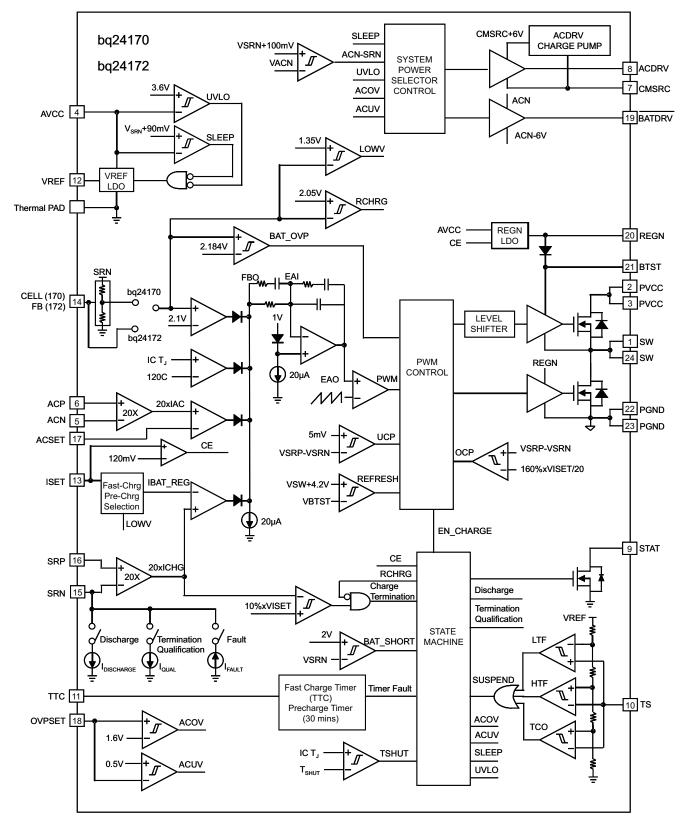


Figure 17. Efficiency vs Output Current (VOUT = 3.8V)

Copyright © 2010–2011, Texas Instruments Incorporated



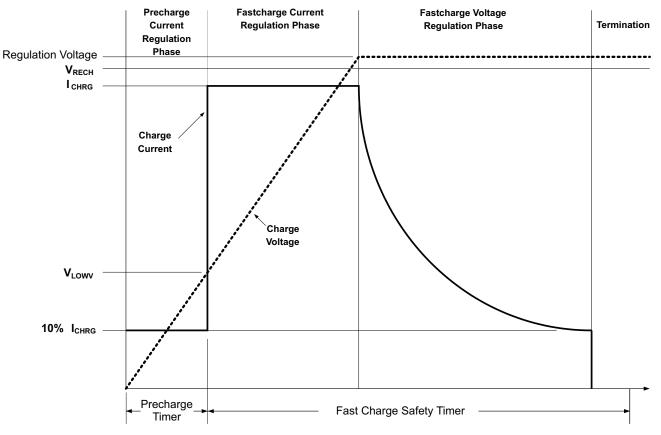
FUNCTIONAL BLOCK DIAGRAM





ISTRUMENTS

EXAS



DETAILED DESCRIPTION

Figure 19. Typical Charging Profile

BATTERY VOLTAGE REGULATION

The bq24170/172 offers a high accuracy voltage regulator on for the charging voltage. The bq24170 uses CELL pin to select number of cells with a fixed 4.2V/cell. Connecting CELL to AGND sets 1 cell output, floating CELL pin sets 2 cell output, and connecting to VREF sets 3 cell output.

CELL PIN	VOLTAGE REGULATION		
AGND	4.2V		
Floating	8.4 V		
VREF	12.6 V		

Table 2. bq24170 CELL Pin Settings

The bq24172 uses external resistor divider for voltage feedback and regulate to internal 2.1V voltage reference on FB pin. Use the following equation for the regulation voltage for bq24172:

$$V_{BAT} = 2.1 \text{ V} \times \left[1 + \frac{\text{R2}}{\text{R1}}\right]$$

(1)

where R2 is connected from FB to the battery and R1 is connected from FB to GND.

BATTERY CURRENT REGULATION

The ISET input sets the maximum charging current. Battery current is sensed by current sensing resistor RSR connected between SRP and SRN. The full-scale differential voltage between SRP and SRN is 40mV max. The equation for charge current is:



$$I_{CHARGE} = \frac{V_{ISET}}{20 \times R_{SR}}$$

(2) The valid input voltage range of ISET is up to 0.8V. With $10m\Omega$ sense resistor, the maximum output current is

The charger is disabled when ISET pin voltage is below 40mV and is enabled when ISET pin voltage is above 120mV. For 10m Ω current sensing resistor, the minimum fast charge current must be higher than 600mA.

Under high ambient temperature, the charge current will fold back to keep IC temperature not exceeding 120°C.

BATTERY PRECHARGE CURRENT REGULATION

4A. With $20m\Omega$ sense resistor, the maximum output current is 2A.

On Power-up, if the battery voltage is below the V_{LOWV} threshold, the bq24170/172 applies the pre-charge current to the battery. This pre-charge feature is intended to revive deeply discharged cells. If the VLOWV threshold is not reached within 30 minutes of initiating pre-charge, the charger turns off and a FAULT is indicated on the status pins.

For bq24170/172, the pre-charge current is set as 10% of the fast charge rate set by ISET voltage.

$$I_{\text{PRECHARGE}} = \frac{V_{\text{ISET}}}{200 \times R_{\text{SR}}}$$

INPUT CURRENT REGULATION

The total input current from an AC adapter or other DC sources is a function of the system supply current and the battery charging current. System current normally fluctuated as portions of the systems are powered up or down. Without Dynamic Power Management (DPM), the source must be able to supply the maximum system current and the maximum available charger input current simultaneously. By using DPM, the input current regulator reduces the charging current when the summation of system power and charge power exceeds the maximum input power. Therefore, the current capability of the AC adapter can be lowered, reducing system cost.

Input current is set by the voltage on ACSET pin using the following equation:

$$I_{\text{DPM}} = \frac{V_{\text{ACSET}}}{20 \times R_{\text{AC}}}$$
(4)

The ACP and ACN pins are used to sense across RAC with default value of 10mΩ. However, resistors of other values can also be used. A larger sense resistor will give a larger sense voltage and higher regulation accuracy, at the expense of higher conduction loss.

CHARGE TERMINATION, RECHARGE, AND SAFETY TIMERS

The charger monitors the charging current during the voltage regulation phase. Termination is detected when the SRN voltage (bq24170) or FB voltage (bq24172) is higher than recharge threshold and the charge current is less than the termination current threshold, as calculated below:

$$I_{\text{TERM}} = \frac{V_{\text{ISET}}}{200 \times R_{\text{SR}}}$$

where V_{ISET} is the voltage on the ISET pin and R_{SR} is the sense resistor. There is a 25ms deglitch time during transition between fast-charge and pre-charge.

As a safety backup, the charger also provides an internal fixed 30 minutes pre-charge safety timer and a programmable fast charge timer. The fast charge time is programmed by the capacitor connected between the TTC pin and AGND, and is given by the formula:

$$t_{TTC} = C_{TTC} \times K_{TTC}$$

(6)

(5)

(3)

Where C_{TTC} is the capacitor connected to TTC and K_{TTC} is the constant multiplier.

A new charge cycle is initiated when one of the following conditions occurs:

- The battery voltage falls below the recharge threshold
- A power-on-reset (POR) event occurs
- ISET pin toggled below 40mV (disable charge) and above 120mV (enable charge)

bq24170 bq24172 SLUSAD2B – NOVEMBER 2010–REVISED APRIL 2011



Pull TTC pin to AGND to disable both termination and fast charge safety timer (reset timer). Pull TTC pin to VREF to disable the safety timer, but allow charge termination.

POWER UP

The charge uses a SLEEP comparator to determine the source of power on the AVCC pin, since AVCC can be supplied either from the battery or the adapter. With the adapter source present, if the AVCC voltage is greater than the SRN voltage, the charger exits SLEEP mode. If all conditions are met for charging, the charger then starts charge the battery (see **the Enabling and Disabling Charging** section). If SRN voltage is greater than AVCC, the charger enters low quiescent current SLEEP mode to minimize current drain from the battery. During SLEEP mode, the VREF output turns off and the STAT pin goes to high impedance.

If AVCC is below the UVLO threshold, the device is disabled.

INPUT UNDER-VOLTAGE LOCK-OUT (UVLO)

The system must have a minimum AVCC voltage to allow proper operation. This AVCC voltage could come from either input adapter or battery, since a conduction path exists from the battery to AVCC through the high side NMOS body diode. When AVCC is below the UVLO threshold, all circuits on the IC are disabled.

INPUT OVER-VOLTAGE/UNDER-VOLTAGE PROTECTION

ACOV provides protection to prevent system damage due to high input voltage. In bq24170/172, once the voltage on OVPSET is above the 1.6V ACOV threshold or below the 0.5V ACUV threshold, charge is disabled and input MOSFETs turn off. The bq24170/172 provides flexibility to set the input qualification threshold.

ENABLE AND DISABLE CHARGING

The following conditions have to be valid before charging is enabled:

- ISET pin above 120mV
- Device is not in Under-Voltage-Lock-Out (UVLO) mode (i.e. V_{AVCC} > V_{UVLO})
- Device is not in SLEEP mode (i.e. V_{AVCC} > V_{SRN})
- OVPSET voltage is between 0.5V and 1.6V to qualify the adapter
- 1.5s delay is complete after initial power-up
- REGN LDO and VREF LDO voltages are at correct levels
- Thermal Shut down (TSHUT) is not valid
- TS fault is not detected
- ACFET turns on (See System Power Selector for details)

One of the following conditions stops on-going charging:

- ISET pin voltage is below 40mV
- Device is in UVLO mode
- Adapter is removed, causing the device to enter SLEEP mode
- · OVPSET voltage indicates the adapter is not valid
- REGN or VREF LDO voltage is overloaded
- TSHUT temperature threshold is reached
- TS voltage goes out of range indicating the battery temperature is too hot or too cold
- ACFET turns off
- TTC timer expires or pre-charge timer expires

SYSTEM POWER SELECTOR

The IC automatically switches adapter or battery power to the system load. The battery is connected to the system by default during power up or during SLEEP mode. When the adapter plugs in and the voltage is above the battery voltage, the IC exits SLEEP mode. The battery is disconnected from the system and the adapter is connected to the system after exiting SLEEP. An automatic break-before-make logic prevents shoot-through currents when the selectors switch.



The ACDRV is used to drive a pair of back-to-back n-channel power MOSFETs between adapter and ACP with sources connected together to CMSRC. The n-channel FET with the drain connected to the ACP (Q2, RBFET) provides reverse battery discharge protection, and minimizes system power dissipation with its low-RDS_{ON}. The other n-channel FET with drain connected to adapter input (Q1, ACFET) separates battery from adapter, and provides a limited dl/dt when connecting the adapter to the system by controlling the FET turn-on time. The /BATDRV controls a p-channel power MOSFET (Q3, BATFET) placed between battery and system with drain connected to battery.

Before the adapter is detected, the ACDRV is pulled to CMSRC to keep ACFET off, disconnecting the adapter from system. /BATDRV stays at ACN-6V (clamp to ground) to connect battery to system if all the following conditions are valid:

- $V_{AVCC} > V_{UVLO}$ (battery supplies AVCC)
- V_{ACN} < V_{SRN} + 200 mV

After the device comes out of SLEEP mode, the system begins to switch from battery to adapter. The AVCC voltage has to be 300mV above SRN to enable the transition. The break-before-make logic keeps both ACFET and BATFET off for 10us before ACFET turns on. This prevents shoot-through current or any large discharging current from going into the battery. The /BATDRV is pulled up to ACN and the ACDRV pin is set to CMSRC + 6V by an internal charge pump to turn on n-channel ACFET, connecting the adapter to the system if all the following conditions are valid:

- V_{ACUV} < V_{OVPSET} < V_{ACOV}
- V_{AVCC} > V_{SRN} + 300 mV

When the adapter is removed, the IC turns off ACFET and enters SLEEP mode.

BATFET keeps off until the system drops close to SRN. The BATDRV pin is driven to ACN - 6V by an internal regulator to turn on p-channel BATFET, connecting the battery to the system.

Asymmetrical gate drive provides fast turn-off and slow turn-on of the ACFET and BATFET to help the break-before-make logic and to allow a soft-start at turn–on of both MOSFETs. The delay time can be further increased, by putting a capacitor from gate to source of the power MOSFETs.

CONVERTER OPERATION

The bq24170/172 employs a 1.6MHz constant-frequency step-down switching regulator. The fixed frequency oscillator keeps tight control of the switching frequency under all conditions of input voltage, battery voltage, charge current, and temperature, simplifying output filter design and keeping it out of the audible noise region.

A type III compensation network allows using ceramic capacitors at the output of the converter. An internal saw-tooth ramp is compared to the internal error control signal to vary the duty-cycle of the converter. The ramp height is proportional to the AVCC voltage to cancel out any loop gain variation due to a change in input voltage, and simplifies the loop compensation. Internal gate drive logic allows achieving 97% duty-cycle before pulse skipping starts.

AUTOMATIC INTERNAL SOFT-START CHARGER CURRENT

The charger automatically soft-starts the charger regulation current every time the charger goes into fast-charge to ensure there is no overshoot or stress on the output capacitors or the power converter. The soft-start consists of stepping-up the charge regulation current into 8 evenly divided steps up to the programmed charge current. Each step lasts around 1.6ms, for a typical rise time of 12.8ms. No external components are needed for this function.

CHARGE OVER-CURRENT PROTECTION

The charger monitors top side MOSFET current by high side sense FET. When peak current exceeds MOSFET limit, it will turn off the top side MOSFET and keep it off until the next cycle. The charger has a secondary cycle-to-cycle over-current protection. It monitors the charge current, and prevents the current from exceeding 160% of the programmed charge current. The high-side gate drive turns off when either over-current condition is detected, and automatically resumes when the current falls below the over-current threshold.

Copyright © 2010–2011, Texas Instruments Incorporated



CHARGE UNDER-CURRENT PROTECTION

After the recharge, if the SRP-SRN voltage decreases below 5mV, the low side FET will be turned off for the rest of the switching cycle. During discontinuous conduction mode (DCM), the low side FET will only turn on for a short period of time when the boostrap capacitor voltage drops below 4V to provide refresh charge for the capacitor. This is important to prevent negative inductor current from causing any boost effect in which the input voltage increases as power is transferred from the battery to the input capacitors. This can lead to an over-voltage on the AVCC node and potentially cause damage to the system.

BATTERY DETECTION

For applications with removable battery packs, IC provides a battery absent detection scheme to reliably detect insertion or removal of battery packs. The battery detection routine runs on power up, or if battery voltage falls below recharge threshold voltage due to removing a battery or discharging a battery.

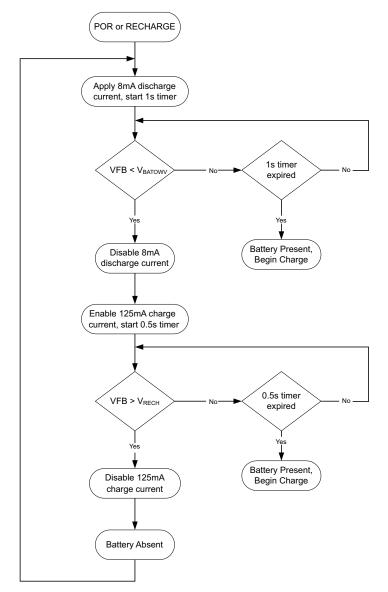


Figure 20. Battery Detection Flowchart

Copyright © 2010–2011, Texas Instruments Incorporated



Once the device has powered up, a 8-mA discharge current is applied to the SRN terminal. If the battery voltage falls below the LOWV threshold within 1 second, the discharge source is turned off, and the charger is turned on at low charge current (125mA). If the battery voltage gets up above the recharge threshold within 500ms, there is no battery present and the cycle restarts. If either the 500ms or 1 second timer time out before the respective thresholds are hit, a battery is detected and a charge cycle is initiated.

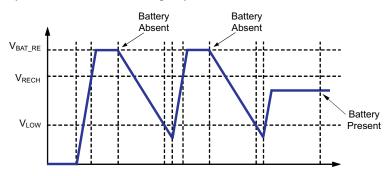


Figure 21. Battery Detect Timing Diagram

Care must be taken that the total output capacitance at the battery node is not so large that the discharge current source cannot pull the voltage below the LOWV threshold during the 1 second discharge time. The maximum output capacitances can be calculated according to the following equations:

$$C_{MAX} = \frac{I_{DISCH} \times I_{DISCH}}{(4.1 \text{ V} - 2.9 \text{ V}) \times \text{Number of cells}} (\text{for bq24170})$$

$$C_{MAX} = \frac{I_{DISCH} \times I_{DISCH}}{(2.05 \text{ V} - 1.45 \text{ V}) \times \left[1 + \frac{R_2}{R_1}\right]} (\text{for bq24172})$$
(8)

Where C_{MAX} is the maximum output capacitance, I_{DISCH} is the discharge current, t_{DISCH} is the discharge time, and R_2 and R_1 are the voltage feedback resistors from the battery to the FB pin.

Example

For a 3-cell Li+ charger, with $R_2 = 500k\Omega$, $R_1 = 100k\Omega$ (giving 12.6V for voltage regulation), $I_{DISCH} = 8mA$, $t_{DISCH} = 1$ second.

$$C_{MAX} = \frac{8 \text{ mA} \times 1 \text{ sec}}{0.6 \text{ V} \times \left[1 + \frac{500 \text{ k}\Omega}{100 \text{ k}\Omega}\right]} = 2.2 \text{ mF}$$
(9)

Based on these calculations, no more than 2200 μ F should be allowed on the battery node for proper operation of the battery detection circuit.

BATTERY SHORT PROTECTION

When SRN pin voltage is lower than 2V it is considered as battery short condition during charging period. The charger will shut down immediately for 1ms, then soft start back to the charging current the same as precharge current. This prevents high current may build in output inductor and cause inductor saturation when battery terminal is shorted during charging. The converter works in non-synchronous mode during battery short.

BATTERY OVER-VOLTAGE PROTECTION

The converter will not allow the high-side FET to turn-on until the battery voltage goes below 102% of the regulation voltage. This allows one-cycle response to an over-voltage condition – such as occurs when the load is removed or the battery is disconnected. A total 6mA current sink from SRP/SRN to AGND allows discharging the stored output inductor energy that is transferred to the output capacitors. If battery over-voltage condition lasts for more than 30ms, charge is disabled.

Copyright © 2010–2011, Texas Instruments Incorporated



TEMPERATURE QUALIFICATION

The controller continuously monitors battery temperature by measuring the voltage between the TS pin and AGND. A negative temperature coefficient thermistor (NTC) and an external voltage divider typically develop this voltage. The controller compares this voltage against its internal thresholds to determine if charging is allowed. To initiate a charge cycle, the battery temperature must be within the V_{LTF} to V_{HTF} thresholds. If battery temperature is outside of this range, the controller suspends charge and waits until the battery temperature is within the V_{LTF} to V_{HTF} range. During the charge cycle the battery temperature must be within the V_{LTF} to V_{TCO} thresholds. If battery temperature is outside of this range, the controller suspends charge and waits until the battery temperature is outside of this range. The controller suspends charge and waits until the battery temperature is within the V_{LTF} to V_{HTF} to V_{HTF} to V_{HTF} to V_{HTF} to V_{HTF} to V_{HTF} and the battery temperature is outside of this range. The controller suspends charge by turning off the PWM charge MOSFETss. Figure 22 summarizes the operation.

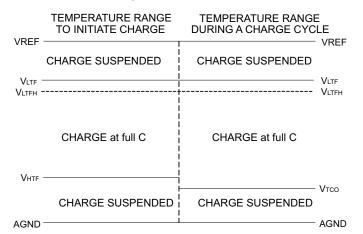


Figure 22. TS Pin, Thermistor Sense Thresholds

Assuming a 103AT NTC thermistor on the battery pack as shown in Figure 23, the values of RT1 and RT2 can be determined by using Equation 10 and Equation 11:

$$RT2 = \frac{V_{VREF} \times RTH_{COLD} \times RTH_{HOT} \times \left(\frac{1}{V_{LTF}} - \frac{1}{V_{TCO}}\right)}{RTH_{HOT} \times \left(\frac{V_{VREF}}{V_{TCO}} - 1\right) - RTH_{COLD} \times \left(\frac{V_{VREF}}{V_{LTF}} - 1\right)}$$
(10)
$$RT1 = \frac{\frac{V_{VREF}}{V_{LTF}} - 1}{\frac{1}{RT2} + \frac{1}{RTH_{COLD}}}$$
(11)

Select 0°C to 45°C range for Li-ion or Li-polymer battery,

RTH_{COLD} = 27.28 kΩ RTH_{HOT} = 4.911 kΩ RT1 = 5.23 kΩ RT2 = 30.1 kΩ

After select closest standard resistor value, by calculating the thermistor resistance at temperature threshold, the final temperature range can be gotten from thermistor datasheet temperature-resistance table.



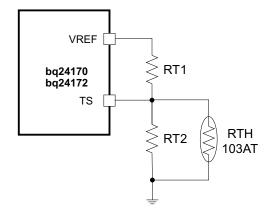


Figure 23. TS Resistor Network

MOSFET SHORT CIRCUIT AND INDUCTOR SHORT CIRCUIT PROTECTION

The IC has a short circuit protection feature. Its cycle-by-cycle current monitoring feature is achieved through monitoring the voltage drop across Rdson of the MOSFETs. The charger will be latched off, but the ACFET keep on to power the system. The only way to reset the charger from latch-off status is remove adapter then plug adapter in again. Meanwhile, STAT is blinking to report the fault condition.

THERMAL REGULATION AND SHUTDOWN PROTECTION

The QFN package has low thermal impedance, which provides good thermal conduction from the silicon to the ambient, to keep junctions temperatures low. The internal thermal regulation loop will fold back the charge current to keep the junction temperature from exceeding 120°C. As added level of protection, the charger converter turns off and self-protects whenever the junction temperature exceeds the TSHUT threshold of 150°C. The charger stays off until the junction temperature falls below 130°C.

TIMER FAULT RECOVERY

The IC provides a recovery method to deal with timer fault conditions. The following summarizes this method:

Condition 1: The battery voltage is above the recharge threshold and a timeout fault occurs.

Recovery Method: The timer fault will clear when the battery voltage falls below the recharge threshold, and battery detection will begin. A POR or taking ISET below 40mV will also clear the fault.

Condition 2: The battery voltage is below the recharge threshold and a timeout fault occurs.

Recovery Method: Under this scenario, the IC applies the fault current to the battery. This small current is used to detect a battery removal condition and remains on as long as the battery voltage stays below the recharge threshold. If the battery voltage goes above the recharge threshold, the IC disabled the fault current and executes the recovery method described in Condition 1. A POR or taking ISET below 40mV will also clear the fault.

INDUCTOR, CAPACITOR, AND SENSE RESISTOR SELECTION GUIDELINES

The IC provides internal loop compensation. With this scheme, the best stability occurs when the LC resonant frequency, f_0 , is approximately 15kHz – 25kHz for the IC.

$$f_{\rm o} = \frac{1}{2\pi\sqrt{\rm LC}}$$

(12)

TEXAS INSTRUMENTS

www.ti.com

Table 3 provides a summary of typical LC components for various charge currents.

CHARGE CURRENT	1A	2A	3A	4A					
Output inductor L	6.8 µH	3.3 µH	3.3 µH	2.2 µH					
Output capacitor C	10 µF	20 µF	20 µF	30 µF					

Table 3. Typical Values as a Function of Charge Current

CHARGE STATUS OUTPUTS

The open-drain STAT outputs indicate various charger operations as listed in Table 4. These status pins can be used to drive LEDs or communicate with the host processor. Note that OFF indicates that the open-drain transistor is turned off.

Table 4. STAT Pin Definition

CHARGE STATE	STAT
Charge in progress (including recharging)	ON
Charge complete, Sleep mode, Charge disabled	OFF
Charge suspend, Input over-voltage, Battery over-voltage, timer fault, , battery absent	BLINK



APPLICATION INFORMATION

INDUCTOR SELECTION

The bq24170/72 has a 1600-kHz switching frequency to allow the use of small inductor and capacitor values. Inductor saturation current should be higher than the charging current (I_{CHG}) plus half the ripple current (I_{RIPPLE}):

$$I_{SAT} \ge I_{CHG} + (1/2)I_{RIPPLE}$$
 (13)

Inductor ripple current depends on input voltage (V_{IN}), duty cycle (D = V_{OUT}/V_{IN}), switching frequency (fs), and inductance (L):

$$I_{RIPPLE} = \frac{V_{IN} \times D \times (1-D)}{fs \times L}$$
(14)

The maximum inductor ripple current happens with D = 0.5 or close to 0.5. Usually inductor ripple is designed in the range of 20% to 40% of the maximum charging current as a trade-off between inductor size and efficiency for a practical design.

INPUT CAPACITOR

The input capacitor should have enough ripple current rating to absorb input switching ripple current. The worst case RMS ripple current is half of the charging current when duty cycle is 0.5. If the converter does not operate at 50% duty cycle, then the worst case capacitor RMS current I_{CIN} occurs where the duty cycle is closest to 50% and can be estimated by the following equation:

$$I_{CIN} = I_{CHG} \times \sqrt{D \times (1 - D)}$$
(15)

A low ESR ceramic capacitor such as X7R or X5R is preferred for the input decoupling capacitor and should be placed as close as possible to the drain of the high-side MOSFET and source of the low-side MOSFET. The voltage rating of the capacitor must be higher than the normal input voltage level. A 25V rating or higher capacitor is preferred for a 15V input voltage. A 20μ F capacitance is suggested for a typical 3A to 4A charging current.

OUTPUT CAPACITOR

The output capacitor also should have enough ripple current rating to absorb output switching ripple current. The output capacitor RMS current I_{COUT} is given as:

$$I_{\text{COUT}} = \frac{I_{\text{RIPPLE}}}{2 \times \sqrt{3}} \approx 0.29 \times I_{\text{RIPPLE}}$$
(16)

The output capacitor voltage ripple can be calculated as follows:

$$\Delta V_{O} = \frac{V_{OUT}}{8LCfs^2} \left(1 - \frac{V_{OUT}}{V_{IN}} \right)$$
(17)

At certain input/output voltages and switching frequencies, the voltage ripple can be reduced by increasing the output filter LC.

The bq24170/72 has an internal loop compensator. To achieve good loop stability, the resonant frequency of the output inductor and output capacitor should be designed between 15 kHz and 25 kHz. The preferred ceramic capacitor has a 25V or higher rating, X7R or X5R.

INPUT FILTER DESIGN

During adapter hot plug-in, the parasitic inductance and the input capacitor from the adapter cable form a second order system. The voltage spike at the AVCC pin may be beyond the IC maximum voltage rating and damage the IC. The input filter must be carefully designed and tested to prevent an over-voltage event on the AVCC pin.

There are several methods to damping or limiting the over-voltage spike during adapter hot plug-in. An electrolytic capacitor with high ESR as an input capacitor can damp the over-voltage spike well below the IC maximum pin voltage rating. A high current capability TVS Zener diode can also limit the over-voltage level to an IC safe level. However, these two solutions may not be lowest cost or smallest size.

Copyright © 2010–2011, Texas Instruments Incorporated

bq24170 bq24172 slusAd2B-NOVEMBER 2010-REVISED APRIL 2011



A cost effective and small size solution is shown in Figure 24. R1 and C1 are composed of a damping RC network to damp the hot plug-in oscillation. As a result, the over-voltage spike is limited to a safe level. D1 is used for reverse voltage protection for the AVCC pin. C2 is the AVCC pin decoupling capacitor and it should be placed as close as possible to the AVCC pin. R2 and C2 form a damping RC network to further protect the IC from high dv/dt and high voltage spike. The C2 value should be less than the C1 value so R1 can dominant the equivalent ESR value to get enough damping effect for hot plug-in. R1 and R2 must be sized enough to handle in-rush current power loss according to the resistor manufacturer's datasheet. The filter component values always need to be verified with a real application and minor adjustments may be needed to fit in the real application circuit.

If the input is 5V (USB host or USB adapter), the D1 can be saved. R2 has to be 5Ω or higher to limit the current if the input reversely inserted.

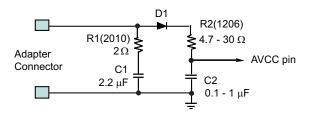


Figure 24. Input Filter

INPUT ACFET AND RBFET SELECTION

N-type MOSFETs are used as input ACFET(Q1) and RBFET(Q2) for better cost effective and small size solution, as shown in Figure 22. Normally, there are around 50uF capacitor totally connected at PVCC node --- 10uF capacitor for buck converter of bq24170/2 and 40uF capacitor for system side. There is a surge current during Q1 turn-on period when a valid adapter is inserted. Decreasing the turn-on speed of Q1 can limit this surge current in desirable range by selecting a MOSFET with relative bigger C_{GD} and/or C_{GS} . At the case Q1 turn on too fast, we need add external C_{GD} and/or C_{GS} . For example, 4.7nF C_{GD} and 47nF C_{GS} are adopted on EVM while using NexFET CSD17313 as Q1.

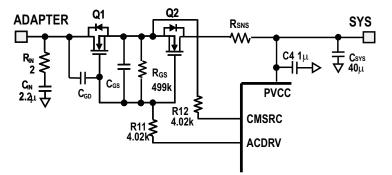


Figure 25. Input ACFET and RBFET

PCB LAYOUT

The switching node rise and fall times should be minimized for minimum switching loss. Proper layout of the components to minimize the high frequency current path loop (see Figure 26) is important to prevent electrical and magnetic field radiation and high frequency resonant problems. The following is a PCB layout priority list for proper layout. Layout of the PCB according to this specific order is essential.

- 1. Place input capacitor as close as possible to the PVCC supply and ground connections and use the shortest copper trace connection. These parts should be placed on the same layer of the PCB instead of on different layers and using vias to make this connection.
- 2. Place the inductor input terminal as close as possible to the SW terminal. Minimize the copper area of this trace to lower electrical and magnetic field radiation but make the trace wide enough to carry the charging current. Do not use multiple layers in parallel for this connection. Minimize parasitic capacitance from this



area to any other trace or plane.

- 3. The charging current sensing resistor should be placed right next to the inductor output. Route the sense leads connected across the sensing resistor back to the IC in the same layer, close to each other (minimize loop area) and do not route the sense leads through a high-current path (see Figure 27 for Kelvin connection for best current accuracy). Place decoupling capacitor on these traces next to the IC.
- 4. Place output capacitor next to the sensing resistor output and ground.
- 5. Output capacitor ground connections need to be tied to the same copper that connects to the input capacitor ground before connecting to system ground.
- 6. Route analog ground separately from power ground and use a single ground connection to tie charger power ground to charger analog ground. Just beneath the IC use analog ground copper pour but avoid power pins to reduce inductive and capacitive noise coupling. Use the thermal pad as a single ground connection point to connect analog ground and power ground together, or use a 0-Ω resistor to tie analog ground to power ground. A star-connection under the thermal pad is highly recommended.
- 7. It is critical that the exposed thermal pad on the backside of the IC package be soldered to the PCB ground. Ensure that there are sufficient thermal vias directly under the IC, connecting to the ground plane on the other layers.
- 8. Decoupling capacitors should be placed next to the IC pins and make trace connection as short as possible.
- 9. The number and physical size of the vias should be enough for a given current path.

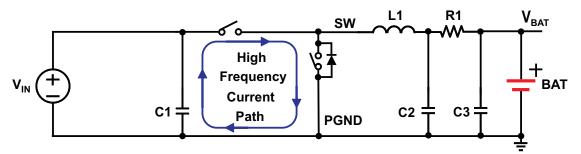


Figure 26. High Frequency Current Path

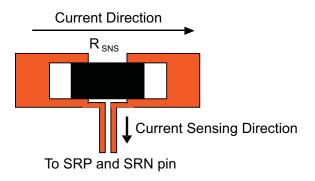


Figure 27. Sensing Resistor PCB Layout

Page

STRUMENTS

EXAS

REVISION HISTORY

Changes from Revision A (November 2010) to Revision B

•	Changed FEATURES third bullet to 30V Input Rating with Adjustable Over-Voltage Protection and added sub-bullet: 4.5V to 17V Input Operating Voltage Range	1
•	Added a new paragraph in DESCRIPTION on page 2, second paragraph	2
•	Deleted last sentence in Pin NO. 19, Description column	3
•	Added diode between BTST and REGN pins in Figure 3	6
•	Added diode between BTST and REGN pins in Figure 4	7
•	Added 2nd row in the ABS MAX TABLE, moving AVCC,STAT from first row to second row and adding -0.3 to 30 in Value column. Also moved ACDRV to this row from next row	8
•	Changed RECOMMENDED OPERATING CONDITIONS Output current row, MIN column from 600 to 0.6	8
•	Changed MIN and MAX columns from 1.55 to 1.57, and 1.65 to 1.63 in first row under INPUT OVER-VOLTAGE COMPARATOR (ACOV) section in ELECTRICAL CHARACTERISTICS table	11
•	Changed MIN, TYP, MAX column from 0.45 to 0.487, 0.5 to 0.497 and 0.55 to 0.507 in first row under INPUT UNDER-VOLTAGE COMPARATOR (ACUV) section in ELECTRICAL CHARACTERISTICS table	11
•	Added paragraph to INPUT FILTER DESIGN section	28

RGY (R-PVQFN-N24)

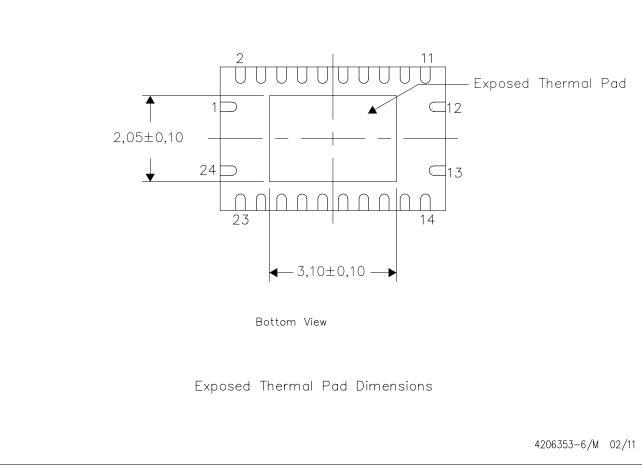
PLASTIC QUAD FLATPACK NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

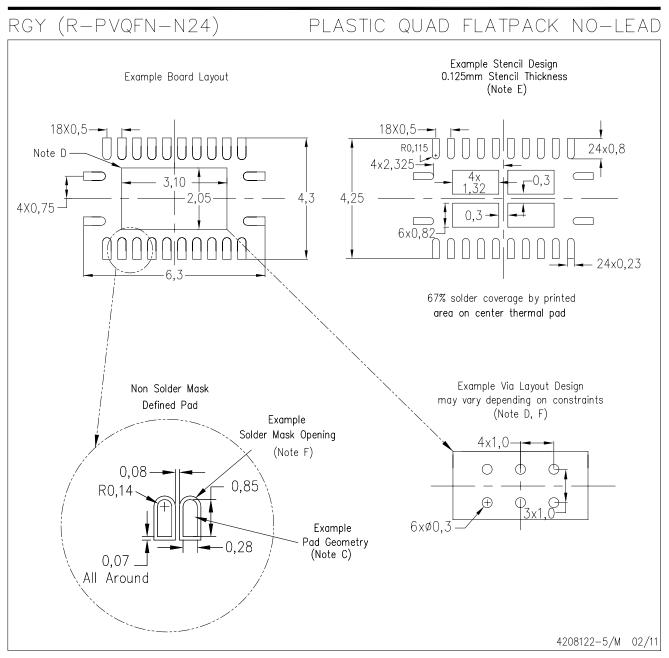
For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



NOTE: A. All linear dimensions are in millimeters





NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat-Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <http://www.ti.com>.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.



24-Jan-2013

PACKAGING INFORMATION

Orderable Device	Status	Package Type	•	Pins	Package Qty	Eco Plan	Lead/Ball Finish		Op Temp (°C)		Samples
	(1)		Drawing			(2)		(3)		(4)	
BQ24170RGYR	ACTIVE	VQFN	RGY	24	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ24170	Samples
BQ24170RGYT	ACTIVE	VQFN	RGY	24	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ24170	Samples
BQ24172RGYR	ACTIVE	VQFN	RGY	24	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ24172	Samples
BQ24172RGYT	ACTIVE	VQFN	RGY	24	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ24172	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ Only one of markings shown within the brackets will appear on the physical device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.





24-Jan-2013

PACKAGE MATERIALS INFORMATION

www.ti.com

Texas Instruments

TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



All dimensions are nomina Device	1	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
BQ24170RGYR	VQFN	RGY	24	3000	330.0	12.4	3.8	5.8	1.2	8.0	12.0	Q1
BQ24170RGYT	VQFN	RGY	24	250	180.0	12.4	3.8	5.8	1.2	8.0	12.0	Q1
BQ24172RGYR	VQFN	RGY	24	3000	330.0	12.4	3.8	5.8	1.2	8.0	12.0	Q1
BQ24172RGYT	VQFN	RGY	24	250	180.0	12.4	3.8	5.8	1.2	8.0	12.0	Q1

TEXAS INSTRUMENTS

www.ti.com

PACKAGE MATERIALS INFORMATION

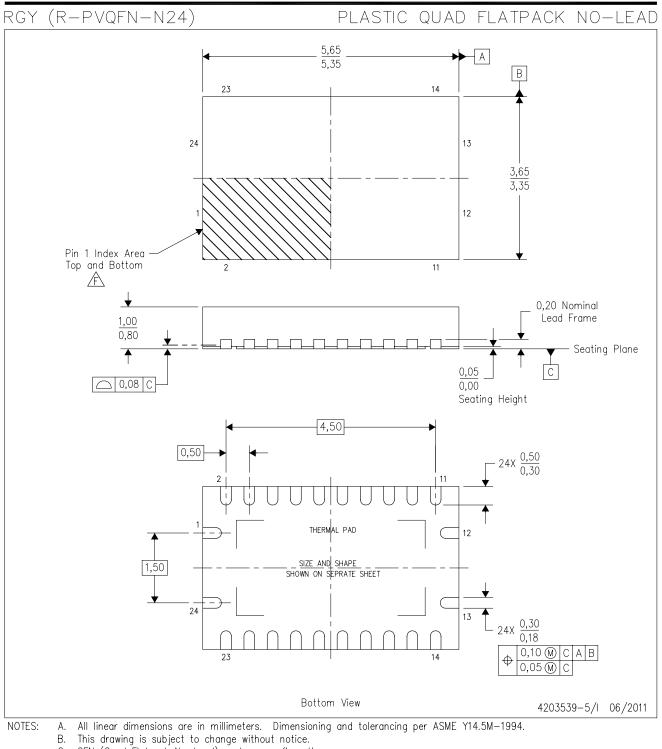
26-Jan-2013



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
BQ24170RGYR	VQFN	RGY	24	3000	367.0	367.0	35.0
BQ24170RGYT	VQFN	RGY	24	250	210.0	185.0	35.0
BQ24172RGYR	VQFN	RGY	24	3000	367.0	367.0	35.0
BQ24172RGYT	VQFN	RGY	24	250	210.0	185.0	35.0

MECHANICAL DATA



- C. QFN (Quad Flatpack No-Lead) package configuration.
- D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
- earrow Pin 1 identifiers are located on both top and bottom of the package and within the zone indicated.
- The Pin 1 identifiers are either a molded, marked, or metal feature.
- G. Package complies to JEDEC MO-241 variation BA.



RGY (R-PVQFN-N24)

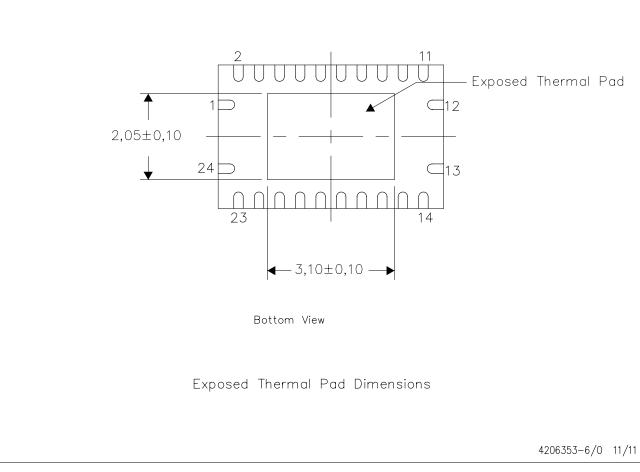
PLASTIC QUAD FLATPACK NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

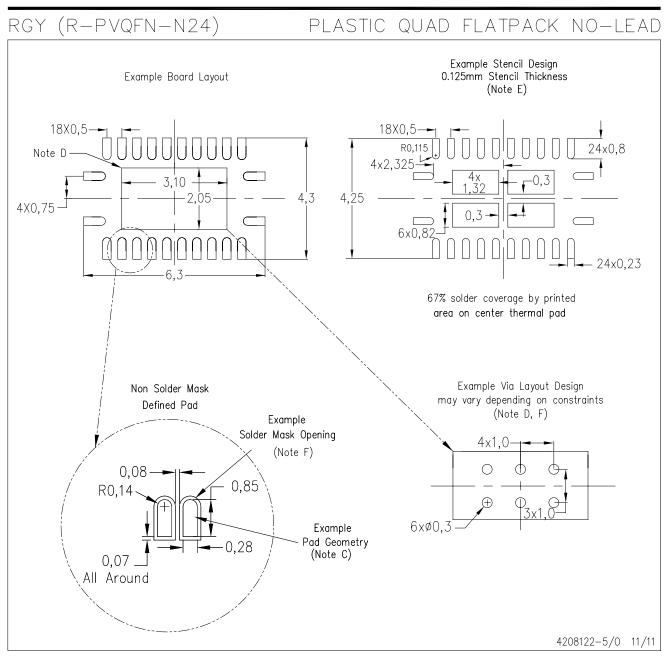
For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



NOTE: All linear dimensions are in millimeters





NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat-Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <http://www.ti.com>.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.



IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in TI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

TI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using TI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI components or services are used. Information published by TI regarding third-party products or services does not constitute a license to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of significant portions of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI components or services with statements different from or beyond the parameters stated by TI for that component or service voids all express and any implied warranties for the associated TI component or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyer acknowledges and agrees that it is solely responsible for compliance with all legal, regulatory and safety-related requirements concerning its products, and any use of TI components in its applications, notwithstanding any applications-related information or support that may be provided by TI. Buyer represents and agrees that it has all the necessary expertise to create and implement safeguards which anticipate dangerous consequences of failures, monitor failures and their consequences, lessen the likelihood of failures that might cause harm and take appropriate remedial actions. Buyer will fully indemnify TI and its representatives against any damages arising out of the use of any TI components in safety-critical applications.

In some cases, TI components may be promoted specifically to facilitate safety-related applications. With such components, TI's goal is to help enable customers to design and create their own end-product solutions that meet applicable functional safety standards and requirements. Nonetheless, such components are subject to these terms.

No TI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Only those TI components which TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components which have *not* been so designated is solely at the Buyer's risk, and that Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components as meeting ISO/TS16949 requirements, mainly for automotive use. In any case of use of non-designated products, TI will not be responsible for any failure to meet ISO/TS16949.

Products		Applications	
Audio	www.ti.com/audio	Automotive and Transportation	www.ti.com/automotive
Amplifiers	amplifier.ti.com	Communications and Telecom	www.ti.com/communications
Data Converters	dataconverter.ti.com	Computers and Peripherals	www.ti.com/computers
DLP® Products	www.dlp.com	Consumer Electronics	www.ti.com/consumer-apps
DSP	dsp.ti.com	Energy and Lighting	www.ti.com/energy
Clocks and Timers	www.ti.com/clocks	Industrial	www.ti.com/industrial
Interface	interface.ti.com	Medical	www.ti.com/medical
Logic	logic.ti.com	Security	www.ti.com/security
Power Mgmt	power.ti.com	Space, Avionics and Defense	www.ti.com/space-avionics-defense
Microcontrollers	microcontroller.ti.com	Video and Imaging	www.ti.com/video
RFID	www.ti-rfid.com		
OMAP Applications Processors	www.ti.com/omap	TI E2E Community	e2e.ti.com
Wireless Connectivity	www.ti.com/wirelessconne	ectivity	

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2013, Texas Instruments Incorporated



Компания «ЭлектроПласт» предлагает заключение долгосрочных отношений при поставках импортных электронных компонентов на взаимовыгодных условиях!

Наши преимущества:

- Оперативные поставки широкого спектра электронных компонентов отечественного и импортного производства напрямую от производителей и с крупнейших мировых складов;
- Поставка более 17-ти миллионов наименований электронных компонентов;
- Поставка сложных, дефицитных, либо снятых с производства позиций;
- Оперативные сроки поставки под заказ (от 5 рабочих дней);
- Экспресс доставка в любую точку России;
- Техническая поддержка проекта, помощь в подборе аналогов, поставка прототипов;
- Система менеджмента качества сертифицирована по Международному стандарту ISO 9001;
- Лицензия ФСБ на осуществление работ с использованием сведений, составляющих государственную тайну;
- Поставка специализированных компонентов (Xilinx, Altera, Analog Devices, Intersil, Interpoint, Microsemi, Aeroflex, Peregrine, Syfer, Eurofarad, Texas Instrument, Miteq, Cobham, E2V, MA-COM, Hittite, Mini-Circuits, General Dynamics и др.);

Помимо этого, одним из направлений компании «ЭлектроПласт» является направление «Источники питания». Мы предлагаем Вам помощь Конструкторского отдела:

- Подбор оптимального решения, техническое обоснование при выборе компонента;
- Подбор аналогов;
- Консультации по применению компонента;
- Поставка образцов и прототипов;
- Техническая поддержка проекта;
- Защита от снятия компонента с производства.



Как с нами связаться

Телефон: 8 (812) 309 58 32 (многоканальный) **Факс:** 8 (812) 320-02-42 **Электронная почта:** <u>org@eplast1.ru</u> **Адрес:** 198099, г. Санкт-Петербург, ул. Калинина, дом 2, корпус 4, литера А.